

Topological Phase Transitions Driven by Sn Doping in $(\text{Mn}_{1-x}\text{Sn}_x)\text{Bi}_2\text{Te}_4$

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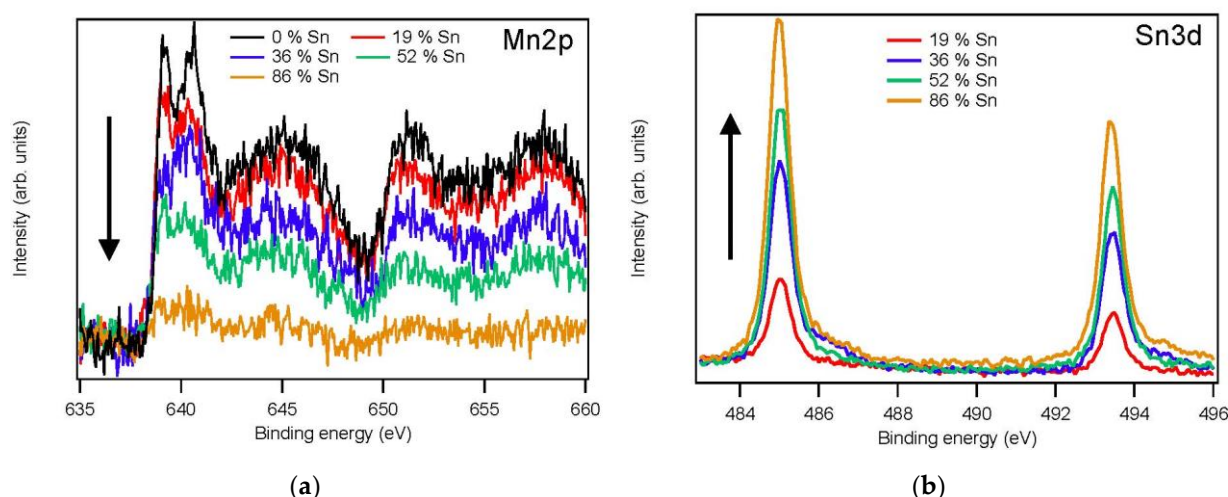


Figure S1. XPS spectra for Mn2p (a) and Sn3d (b) core levels for samples with different Sn concentrations. The spectra are marked with the corresponding percentage of estimated Sn content. The arrows show the change in intensity of the spectra with increasing Sn concentration. The measurements were taken at a photon energy of 1486.7 eV.

XPS measurements were carried out on the SPECS ProvenX-ARPES setup. The spectra were processed and concentrations were estimated in the SpecsLab Prodigy program using the built-in ISQAR function. The figures show the XPS spectra for the samples from which the ARPES data was obtained in Fig. 3. It can be seen that the intensity of the Mn2p peak gradually decreases, while the intensity of the Sn3d peak increases. It is worth noting that the value of the XPS estimation error can be within a few percent. This error does not affect the conclusions drawn in the work.